

From the INTERNATIONAL PRELIMINARY EXAMINING AUTHORITY

To:

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E. & F. SEVENOAKS

 PCT

NOTIFICATION OF TRANSMITTAL OF THE INTERNATIONAL PRELIMINARY EXAMINATION REPORT

(PCT Rule 71.1)

IMPORTANT NOTIFICATION

Date of mailing

(day/month/year)

06.08.2004

Applicant's or agent's file reference

030304pct

International filing date (day/month/year)

10.04.2003

Priority date (day/month/year)

13.04.2002

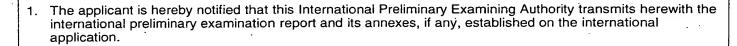
Applicant

PANALYTICAL B.V. et al.

International application No.

PCT/NL 03/00272

G23758W0



- 2. A copy of the report and its annexes, if any, is being transmitted to the International Bureau for communication to all the elected Offices.
- 3. Where required by any of the elected Offices, the International Bureau will prepare an English translation of the report (but not of any annexes) and will transmit such translation to those Offices.

4. REMINDER

The applicant must enter the national phase before each elected Office by performing certain acts (filing translations and paying national fees) within 30 months from the priority date (or later in some Offices) (Article 39(1)) (see also the reminder sent by the International Bureau with Form PCT/IB/301).

Where a translation of the international application must be furnished to an elected Office, that translation must contain a translation of any annexes to the international preliminary examination report. It is the applicant's responsibility to prepare and furnish such translation directly to each elected Office concerned.

For further details on the applicable time limits and requirements of the elected Offices, see Volume II of the PCT Applicant's Guide.

The applicant's attention is drawn to Article 33(5), which provides that the criteria of novelty, inventive step and industrial applicability described in Article 33(2) to (4) merely serve the purposes of international preliminary examination and that "any Contracting State may apply additional or different criteria for the purposes of deciding whether, in that State, the claimed inventions is patentable or not" (see also Article 27(5)). Such additional criteria may relate, for example, to exemptions from patentability, requirements for enabling disclosure, clarity and support for the claims.

Name and mailing address of the international preliminary examining authority:



European Patent Office D-80298 Munich Tel. +49 89 2399 - 0 Tx: 523656 epmu d Fax: +49 89 2399 - 4465 **Authorized Officer**

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INTERNATIONAL PRELIMINARY EXAMINATION REPORT

(PCT Article 36 and Rule 70)

Applicant's or agent's file reference 030304pct International application No. PCT/NL 03/00272			nt's file reference	FOR FURTHE	FOR FURTHER ACTION See Notification of Transmittal of International Preliminary Examination Report (Form PCT/IPEA/416)		
				International filing date (day/month/year) 10.04.2003		Priority date (day/month/year) 13.04.2002	
	nationa N23/		t Classification (IPC) o	or both national classific	ation and IPC		
	cant i	TICAL	. B.V. et al.				
1.	This Auth	interna ority a	ational preliminary e nd is transmitted to	xamination report ha the applicant accordi	s been prepared by th ng to Article 36.	nis International Preliminary Examining	
2.	This	REPO	RT consists of a tot	al of 5 sheets, includ	ling this cover sheet.		
	\boxtimes	been	amended and are t	he basis for this repo	S, i.e. sheets of the de rt and/or sheets conta histrative Instructions	scription, claims and/or drawings which have ining rectifications made before this Authority under the PCT).	
	Thes	•	exes consist of a tot				
			•				
3.	This	report	contains indications	s relating to the follow	ving items:	and the second second	
	ì	×	Basis of the opinion	1			
	1		Priority				
	Ш		•	of opinion with regar	d to novelty, inventive	step and industrial applicability	
	IV		Lack of unity of inve	-	•	·	
	٧	\boxtimes	Reasoned stateme			elty, inventive step or industrial applicability;	
	VI		Certain documents	cited			
	VII		Certain defects in t	he international appli	cation	,	
	VIII		Certain observation	ns on the internationa	l application	·	
Date	of sub	missio	n of the demand		Date of complete	ion of this report	
08.1	1.20	03			06.08.2004		
		examir	address of the internating authority:	tional ·	Authorized Offic	er	
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INTERNATIONAL PRELIMINARY EXAMINATION REPORT

International application No.

PCT/NL 03/00272

	Rasis	of the	report
I.	Dasis	OI IIIE	1 CDOIL

1. With regard to the **elements** of the international application (Replacement sheets which have been furnished to the receiving Office in response to an invitation under Article 14 are referred to in this report as "originally filed" and are not annexed to this report since they do not contain amendments (Rules 70.16 and 70.17)):

				\cdot				
		Des	scription, Pages					
		1-15	5	as originally filed				
		Clai	ims, Numbers					
		1-12	2	received on 04.05.2004 with letter of 30.04.2004				
		Dra	wings, Sheets					
		1-5		as originally filed				
	2.	With regard to the language , all the elements marked above were available or furnished to this Authority in the language in which the international application was filed, unless otherwise indicated under this item.						
		The	ese elements were av	ailable or furnished to this Authority in the following language: , which is:				
			the language of publ	inslation furnished for the purposes of the international search (under Rule 23.1(b)). ication of the international application (under Rule 48.3(b)). Inslation furnished for the purposes of international preliminary examination (under 3).				
3	3.	With regard to any nucleotide and/or amino acid sequence disclosed in the international application, the international preliminary examination was carried out on the basis of the sequence listing:						
			contained in the inte	rnational application in written form.				
			filed together with th	e international application in computer readable form.				
			furnished subsequer	ntly to this Authority in written form.				
			furnished subsequer	ntly to this Authority in computer readable form.				
			The statement that the subsequently furnished written sequence listing does not go beyond the disclosure in the international application as filed has been furnished.					
		The statement that the information recorded in computer readable form is identical to the written sequentiating has been furnished.						
	4.	The	e amendments have r	esulted in the cancellation of:				
			the description,	pages:				
			the claims,	Nos.:				
			tḥe drawings,	sheets:				

INTERNATIONAL PRELIMINARY EXAMINATION REPORT

International application No.

PCT/NL 03/00272

5.	This report has been established as if (some of) the amendments had not been made, since they have
	been considered to go beyond the disclosure as filed (Rule 70.2(c)).

(Any replacement sheet containing such amendments must be referred to under item 1 and annexed to this report.)

6. Additional observations, if necessary:

V. Reasoned statement under Article 35(2) with regard to novelty, inventive step or industrial applicability; citations and explanations supporting such statement

1. Statement

Novelty (N) Yes: Claims 1-12

No: Claims

Inventive step (IS) Yes: Claims 2,9-12

No: Claims 1,3-8

Industrial applicability (IA) Yes: Claims 1-12

No: Claims

2. Citations and explanations

see separate sheet

INTERNATIONAL PRELIMINARY International application No. PCT/NL03/00272 EXAMINATION REPORT - SEPARATE SHEET

D1: NOMA ET AL.: 'Surface-sensitive X-ray fluorescence and diffraction analysis with grazing-exit geometry' X-RAY SPECTROMETRY, vol. 28, 1999, pages 433-439

D2: NOMA ET AL.: 'Micro X-ray diffraction analysis of thin films using grazing-exit conditions' JOURNAL OF SYNCHROTRON RADIATION, vol. 5, 1998, pages 902-904

D4: US-A-5 684 857 (DE BOKX PIETER K) 4 November 1997 (1997-11-04)

Section V

1.1. The subject matter of claim 1 is not inventive:

D1 discloses all features of claim 1 (see chapter "GRAZING EXIT X-RAY DIFFRACTION) except the following novel features:

- 1) the thin layer of the sample is "substantially single crystal"
- 2) the collimator is a slit between the X-ray source and the sample stage

re 1)

The expression "substantially" renders this feature unclear (ISPE Guidelines C-5.38), such that even novelty of this feature is doubtful. It is in any event obvious for the skilled person to try to adapt the grazing exit geometry, which is disclosed in D1 for polycrystalline thin films, also for monocrystalline thin films by conventional measures like rotating the sample, increasing the wavelength range or divergence of the incident beam etc..

re 2)

The skilled person chooses the collimator (for example two slits as in D4 or a single slit with an appropriate source) according to circumstances without the exercise of inventive skill.

Since both features are independent from each other and since both features are obvious, the subject matter of claim 1 is obvious as a whole.

- 1.2. The subject matter of independent use claim 1 defines merely the use of the device of claim 1 without additional novel features and is thus likewise obvious.
- 2. The subject matter of independent method claim 9 appears to be inventive:

INTERNATIONAL PRELIMINARY International application No. PCT/NL03/00272 EXAMINATION REPORT - SEPARATE SHEET

D1 discloses all features of claim 9 except the following novel features:

- 1) the thin layer of the sample is "substantially single crystal"
- 2) the incident beam is "created without a monochromator", i.e polychromatic.

Although feature 1) alone is unclear and obvious for reasons put forward in paragraph 1.1. above, the subject matter of claim 9 is inventive, since both features 1 and 2 are interdependent, such that the skilled person needs two interrelated steps, which implies inventive activity.

It is however to be noted that feature 2) was not contained in any originally filed claim, but only mentioned in the description (p.5,l.31ff) and was thus eventually not searched. Thus an additional search might become necessary in the regional phase. The positive statement with respect to claim 9 (and claim 2 below) has to be seen with this proviso.

- 3.1. The subject matters of dependent claims 2 and 10-12 are likewise new and inventive.
- 3.2. The subject matters of dependent claims 3 to 7 are not inventive, since the additional features defined therein are either disclosed in or obvious from D1.



10/511571 DTO1 Rec'd POT/2001 12 OCT 2004

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CLAIMS:

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1. An X-ray apparatus for high-resolution X-ray diffraction of thin layers of single crystal, comprising:

a sample stage (8) holding a sample (16) having a substantially single crystal thin layer (18) at a front face (12) with the front face (12) oriented substantially normally to a predetermined normal direction (14);

a means (4,6) for generating a collimated beam of X-rays (11) at a predetermined target location (15) on the sample stage at an angle of between 0° and 60° to the normal direction, the beam having an angular divergence at the sample stage in the range 0.01° to 0.20°; and

an X-ray detector (10) arranged laterally of the sample stage for detecting X-rays scattered by the sample (16) to a predetermined range of angles to the normal direction (14), the angles in the predetermined range being in the range from 80° to 90°,

wherein the means for generating a collimated beam of X-rays comprises an X-ray source (4) and a slit (6) between the X-ray source and the sample stage.

- 20 2. An X-ray apparatus according to claim 1 wherein the means for generating a collimated beam does not include a monochromator.
 - 3. An X-ray apparatus according to claim 1 or 2 wherein the X-ray detector (10) has a linear resolution in the normal direction (14) of less than 0.002 times the distance from the X-ray detector to the predetermined target location.
 - 4. X-ray apparatus according to claim 1, 2 or 3 wherein the X-ray source (3) has a dimension of no more than 0.2mm in the direction normal to the beam in the plane containing the normal, the incident beam and the scattered X-rays.





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- 5. An X-ray apparatus according to any preceding claim wherein the X-ray detector (10) is an elongate X-ray detector extending in a direction parallel to the normal direction (14) for detecting in parallel X-rays diffracted by the sample as a function of distance along the normal direction and hence over a predetermined range of angles to the normal direction.
- 6. An X-ray apparatus according to any preceding claim wherein the position sensitive X-ray detector (10) is a solid state detector.
- 7. An X-ray apparatus according to any preceding claim wherein the substantially single crystal thin layer (18) is a semiconductor layer.
- 8. Use of an X-ray apparatus according to any preceding claim to measure the sample (16) the sample (16) being mounted on the sample stage (8) and oriented to diffract the collimated X-ray beam (11) onto the position sensitive X-ray detector (10).
- A method of high-resolution X-ray diffraction; comprising:
 providing a sample stage and an X-ray detector located laterally of the
 sample stage;

mounting a sample having a substantially single crystal thin layer material extending in a plane on the sample stage;

directing an incident collimated beam of x-rays created without a monochromator onto the sample at an angle of 0° to 60° to the normal to the plane; and

measuring with the X-ray detector the X-rays diffracted by the sample to a range of angles in the range 80° to 90° to the normal to the plane.

10. A method according to claim 9 wherein the incident beam has an angular divergence in the range 0.01° to 0.20°.

18

- 11. A method according to claim 9 or 10 wherein the incident beam of X-rays is in a direction from 0° to 40° to the normal to the plane.
- 12. A method according to any of claims 9 to 11 wherein the step of measuring the X-rays diffracted by the sample (16) includes recording the intensity of X-rays incident on the detector (10) simultaneously at a number of locations along the length of the detector.